

Biometric Consortium 2006 Conference

Yooyoung Lee

Guest Researcher

*Computer Security Division of the
Information Technology Laboratory at the
National Institute of Standards and Technology*

100 Bureau Drive, stop 8930

Gaithersburg, MD 20899

Phone: 301.975.8487

yoo.lee@nist.gov

Topic: NIST's Development of Conformance Test Suites for Biometric Interfaces

Abstract: Standards-based conformance testing leads to greatly increased levels of confidence in product conformance claims for developers and users. NIST is working in close collaboration with other government agencies in the development of biometric standards and supporting testing tools. A component of NIST's biometric standards program is the development of Conformance Test Suites (CTS) for biometric interface standards. In February 2006 NIST and DoD Biometrics Task Force released two BioAPI CTS beta implementations. Test results derived from both CTS implementations were cross-validated. NIST is currently developing CTS implementations for selected Common Biometric Exchange Framework Format Patron Formats. This presentation will address NIST's CTS developments in support of national and international biometric standards and will discuss the status of these technical developments.

Biography: Yooyoung Lee is a guest researcher at the Computer Security Division of the Information Technology Laboratory, National Institute of Standards and Technology (NIST). She is a member of the team that is developing conformance testing suites for CBEFF (Common Biometric Exchange File Format) selected Patron Formats. As a PhD student at the Department of Computer Engineering, Chung-Ang University, Seoul, Korea, she was involved in biometrics research (Fingerprint, Face, Iris). She also researched legislation for the use of biometric data by the industry and involved in development of conformance testing suite for BioAPI. Her research interests are computer vision, pattern recognition, biometrics, image processing, and conformance testing.